

FC40SA50FK

HEXFET® Power MOSFET

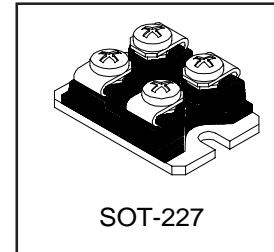
Applications

- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching
- Hard Switched and High Frequency Circuits

V_{DSS}	$R_{DS(on)}$ typ.	I_D
500V	0.084 Ω	40A

Benefits

- Low Gate Charge Q_g results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dv/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Low $R_{DS(on)}$
- Fully Insulated Package



Absolute Maximum Ratings

	Parameter	Max.	Units
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	40	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V$	26	
I_{DM}	Pulsed Drain Current ①	160	
$P_D @ T_C = 25^\circ C$	Power Dissipation	430	W
	Linear Derating Factor	3.45	W/°C
V_{GS}	Gate-to-Source Voltage	± 30	V
dv/dt	Peak Diode Recovery dv/dt ③	9.0	V/ns
T_J	Operating Junction and Storage Temperature Range	-55 to + 150	°C
T_{STG}			

Avalanche Characteristics

Symbol	Parameter	Typ.	Max.	Units
E_{AS}	Single Pulse Avalanche Energy ②	—	1240	mJ
I_{AR}	Avalanche Current ①	—	40	A
E_{AR}	Repetitive Avalanche Energy ①	—	43	mJ

Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
$R_{θJC}$	Junction-to-Case	—	0.29	°C/W
$R_{θCS}$	Case-to-Sink, Flat, Greased Surface	0.05	—	

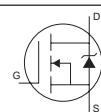
Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(\text{BR})\text{DSS}}$	Drain-to-Source Breakdown Voltage	500	—	—	V	$V_{GS} = 0V, I_D = 250\mu\text{A}$
$\Delta V_{(\text{BR})\text{DSS}/\Delta T_J}$	Breakdown Voltage Temp. Coefficient	—	0.60	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$ ⑥
$R_{DS(\text{on})}$	Static Drain-to-Source On-Resistance	—	0.084	0.10	Ω	$V_{GS} = 10V, I_D = 24\text{A}$ ④
$V_{GS(\text{th})}$	Gate Threshold Voltage	3.0	—	5.0	V	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$
I_{DSS}	Drain-to-Source Leakage Current	—	—	50	μA	$V_{DS} = 500V, V_{GS} = 0V$
		—	—	250		$V_{DS} = 400V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Forward Leakage	—	—	250	nA	$V_{GS} = 30V$
	Gate-to-Source Reverse Leakage	—	—	-250		$V_{GS} = -30V$

Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
g_{fs}	Forward Transconductance	23	—	—	S	$V_{DS} = 50V, I_D = 28A$
Q_g	Total Gate Charge	—	—	270	nC	$I_D = 40A$
Q_{gs}	Gate-to-Source Charge	—	—	84	nC	$V_{DS} = 400V$
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	—	130	nC	$V_{GS} = 10V$, See Fig. 6 and 13 ④
$t_{d(on)}$	Turn-On Delay Time	—	25	—	ns	$V_{DD} = 250V$
t_r	Rise Time	—	140	—		$I_D = 40A$
$t_{d(off)}$	Turn-Off Delay Time	—	55	—		$R_G = 1.0\Omega$
t_f	Fall Time	—	74	—		$V_{GS} = 10V$, See Fig. 10 ④
C_{iss}	Input Capacitance	—	8310	—	pF	$V_{GS} = 0V$
C_{oss}	Output Capacitance	—	960	—		$V_{DS} = 25V$
C_{rss}	Reverse Transfer Capacitance	—	120	—		$f = 1.0\text{MHz}$, See Fig. 5
C_{oss}	Output Capacitance	—	10170	—		$V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$
C_{oss}	Output Capacitance	—	240	—		$V_{GS} = 0V, V_{DS} = 480V, f = 1.0\text{MHz}$
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	440	—		$V_{GS} = 0V, V_{DS} = 0V \text{ to } 480V$ ⑤

Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	40	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	160		
V_{SD}	Diode Forward Voltage	—	—	1	V	$T_J = 25^\circ\text{C}, I_S = 40A, V_{GS} = 0V$ ④
t_{rr}	Reverse Recovery Time	—	620	940	ns	$T_J = 25^\circ\text{C}, I_F = 47A$ $dI/dt = 100A/\mu\text{s}$ ④
Q_{rr}	Reverse Recovery Charge	—	14	21	μC	
I_{RRM}	Reverse Recovery Current	—	38	-	A	$T_J = 25^\circ\text{C}$
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S + L_D$)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See Fig. 11)
- ② Starting $T_J = 25^\circ\text{C}$, $L = 1.55\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 40A$, $dv/dt = 5.5\text{V/ns}$ (See Figure 12a)
- ③ $I_{SD} \leq 40A$, $dI/dt \leq 150A/\mu\text{s}$, $V_{DD} \leq V_{(\text{BR})\text{DSS}}$, $T_J \leq 150^\circ\text{C}$

④ Pulse width $\leq 300\mu\text{s}$; duty cycle $\leq 2\%$.

⑤ $C_{oss \text{ eff.}}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}

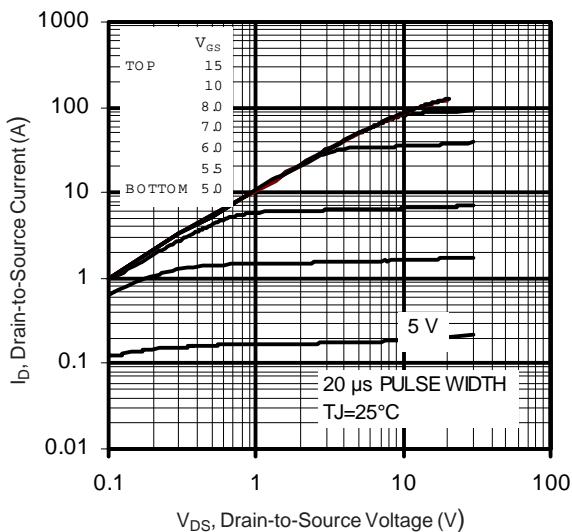


Fig 1. Typical Output Characteristics

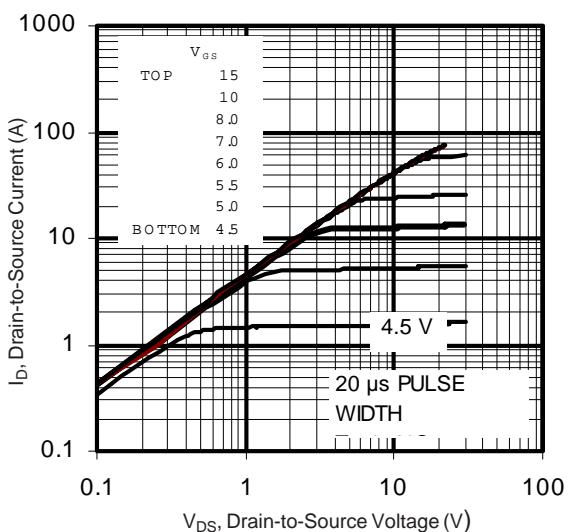


Fig 2. Typical Output Characteristics

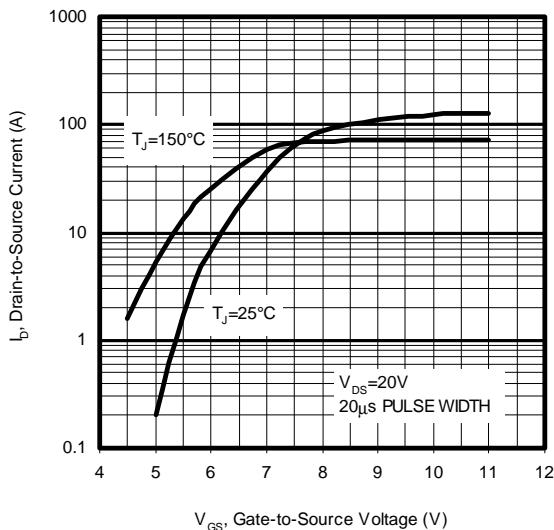


Fig 3. Typical Transfer Characteristics

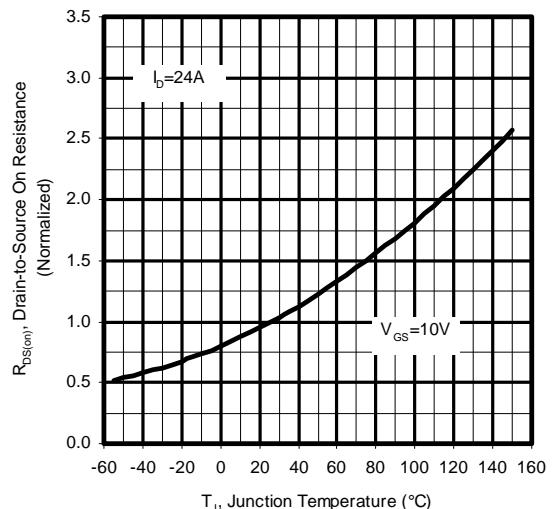


Fig 4. Normalized On-Resistance Vs. Temperature

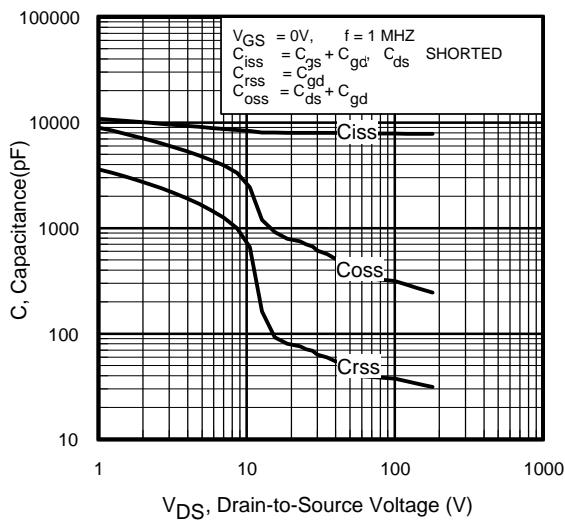


Fig 5. Typical Capacitance Vs.
Drain-to-Source Voltage

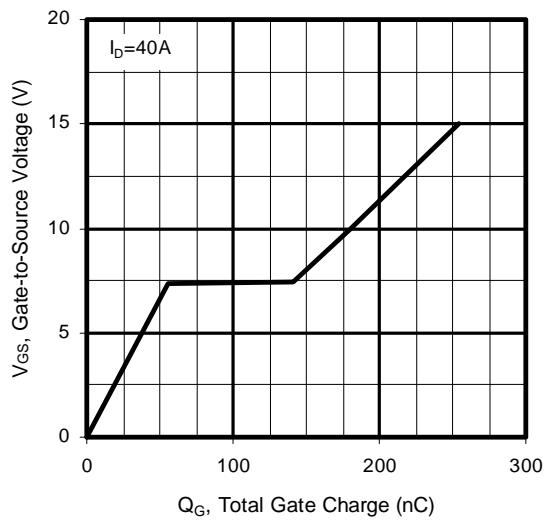


Fig 6. Typical Gate Charge Vs.
Gate-to-Source Voltage

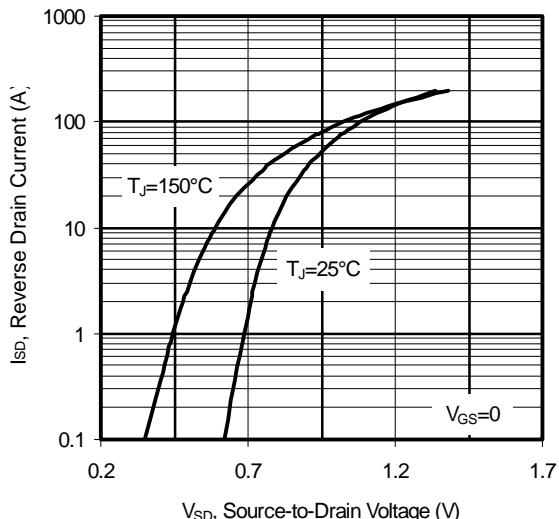


Fig 7. Typical Source-Drain Diode
Forward Voltage

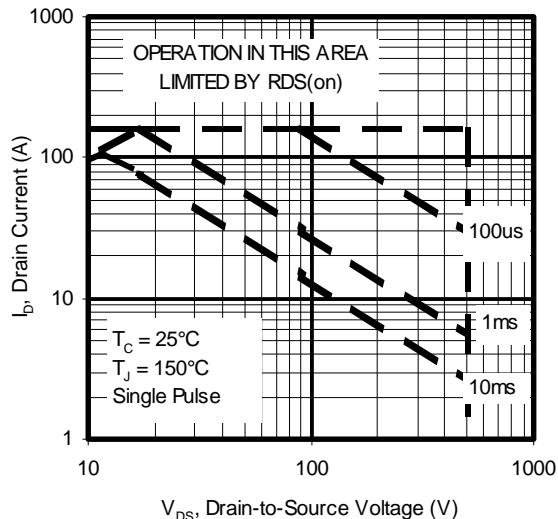


Fig 8. Maximum Safe Operating Area

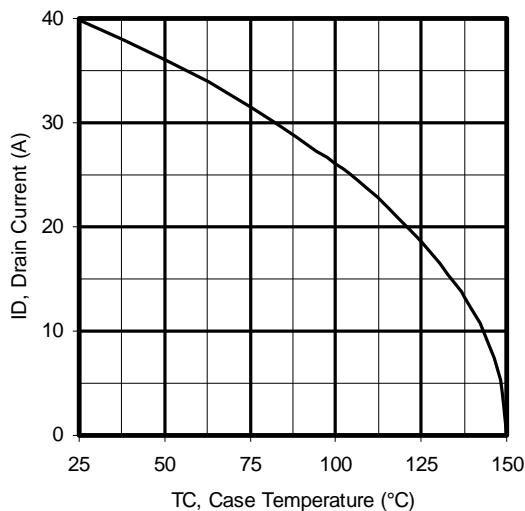


Fig 9. Maximum Drain Current Vs.
Case Temperature

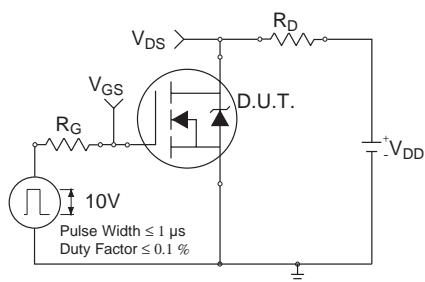


Fig 10a. Switching Time Test Circuit

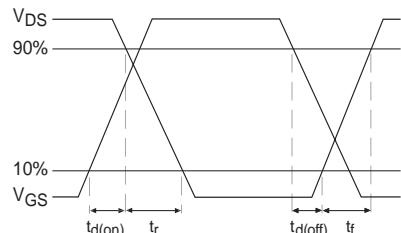


Fig 10b. Switching Time Waveforms

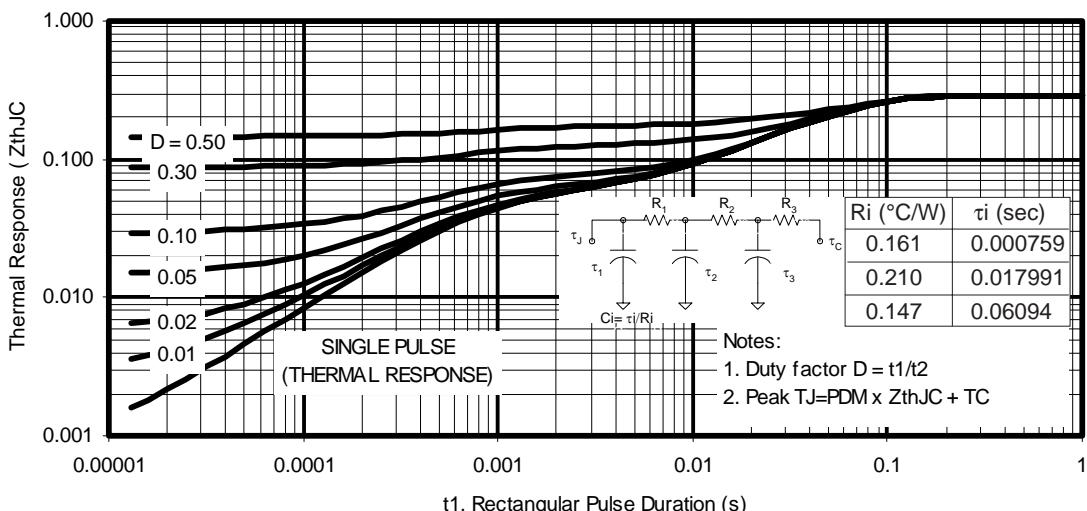


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

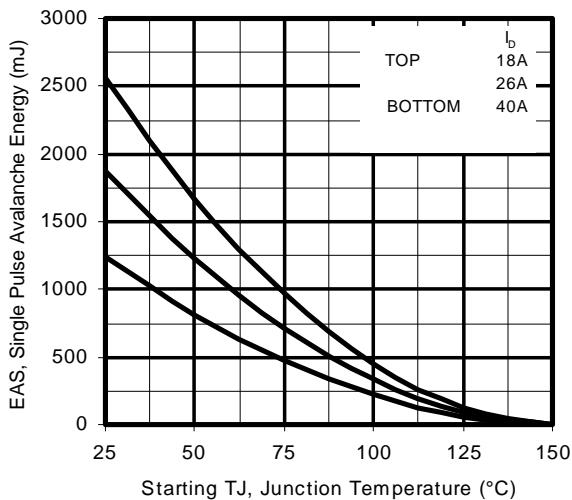


Fig 12a. Maximum Avalanche Energy Vs. Drain Current

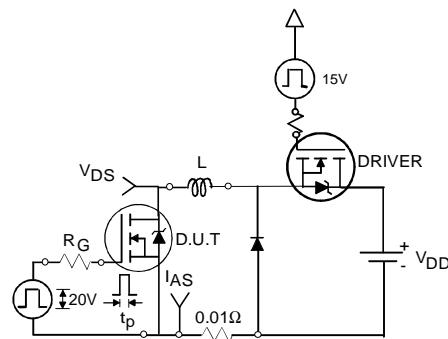


Fig 12c. Unclamped Inductive Test Circuit

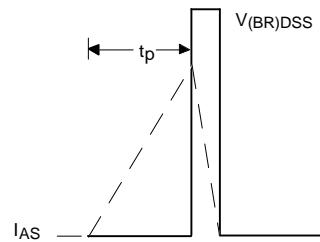


Fig 12d. Unclamped Inductive Waveforms

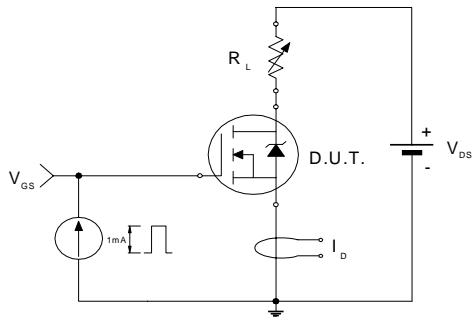


Fig 13a. Gate Charge Test Circuit

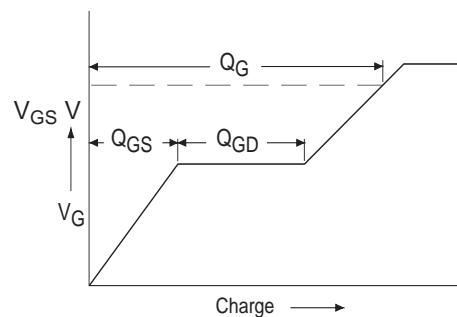
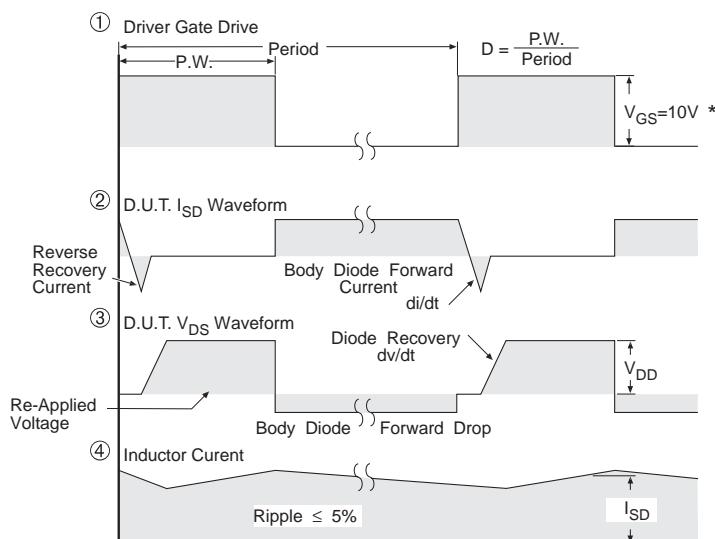
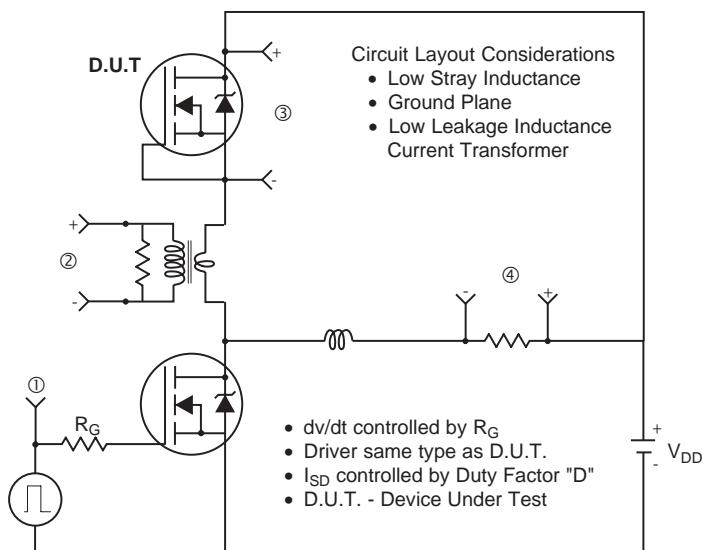


Fig 13b. Basic Gate Charge Waveform

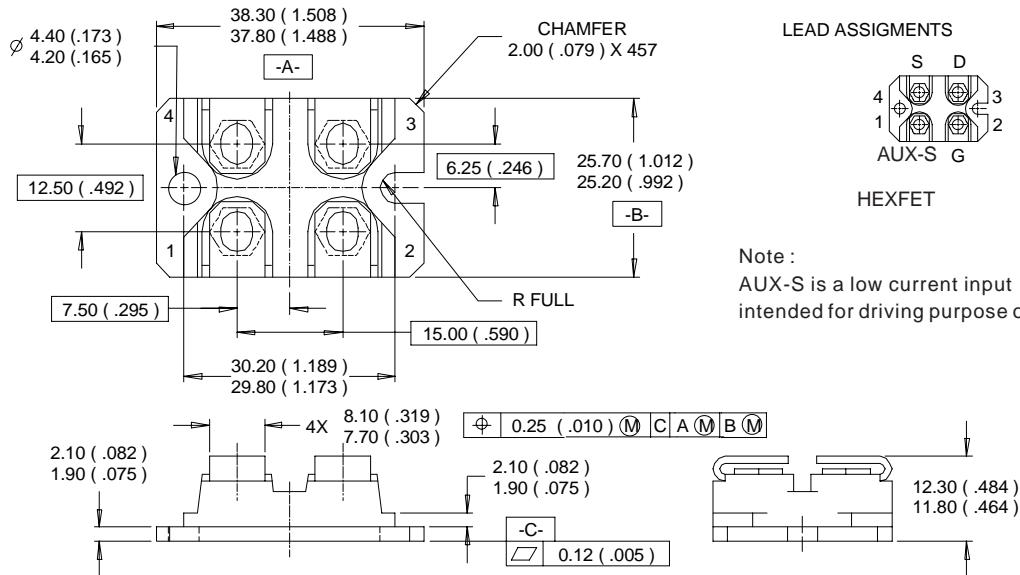
Peak Diode Recovery dv/dt Test Circuit



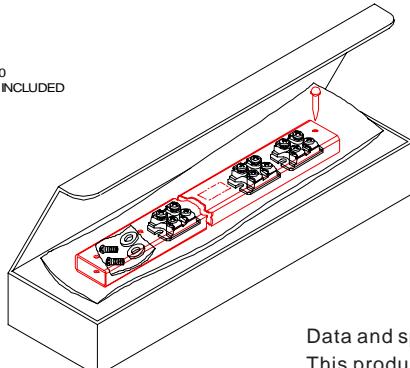
* $V_{GS} = 5V$ for Logic Level Devices

Fig 14. For N-Channel HEXFET® Power MOSFETs

SOT-227 Package Details



QUANTITY PER TUBE IS 10
M4 SCREW AND WASHER INCLUDED



Data and specifications subject to change without notice.
This product has been designed and qualified for Industrial Level.

International
 Rectifier

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